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THE UNITED STATES PATENT & TRADEMARK OFFICE

Applicant: JHE et al. Docket No: 18079-300101  
Serial No: 09/858,350 Group Art Unit 2878  
Filing Date: May 15, 2001 Examiner: Luu, Thanh X.  
For: **HIGH FREQUENCY DITHERING PROBE FOR HIGH SPEED  
SCANNING PROBE MICROSCOPE**

Box Fee Amendment  
Assistant Commissioner for Patents  
Washington, D.C. 20231

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AMENDMENT

Sir:

This Amendment is submitted in response to the Office Action mailed on August 14, 2002, relating to the above-identified application. Applicants respectfully request reconsideration of the patent application in light of the following remarks. Please amend the above-identified application as follows:

In the Claims

Please amend the following claims:

1 1. (Once amended) A high frequency dithering probe for a high speed scanning probe  
2 microscope, comprising:  
3 a high frequency quartz-crystal resonator having a fundamental resonant  
4 frequency in the range of 1MHz ~ 100MHz and a thickness of 0.01mm~2.0mm and having an  
5 electrode attached to a surface of the quartz-crystal resonator; and  
6 a probe attached to the quartz-crystal resonator and having a length of not more  
7 than 2mm.

1 2. (Once amended) The high frequency dithering probe of claim 1, wherein the quartz-  
2 crystal resonator is formed in a flat disk type shape with a plane area of scores of mm<sup>2</sup>